## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | WATANABE ET AL. | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,613,467	09-2003	Chizawa et al.	429/26
*	В	US-6,277,508	08-2001	Reiser et al.	429/17
*	С	US-2002/0051898	05-2002	Moulthrop et al.	429/17
*	D	US-2001/0019793	09-2001	Tsuyoshi, Takahashi	429/39
*	Е	US-2002/0180448	12-2002	Imamura et al.	324/439
*	F	US-2002/0168556	11-2002	Leboe et al.	429/13
	G	US-			
	Ι	US-			
	-	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	WO 00/14819	03-2000	wo	Chizawa et al.	
	0					
	Р					
	α					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	W	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.